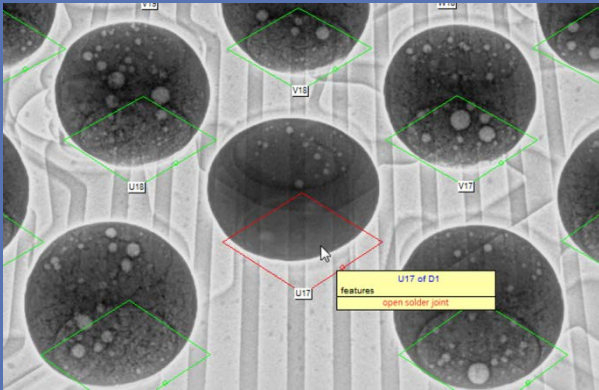


# X-ray System Upgrades

For phoenix microme|x and phoenix nanome|x inspection systems

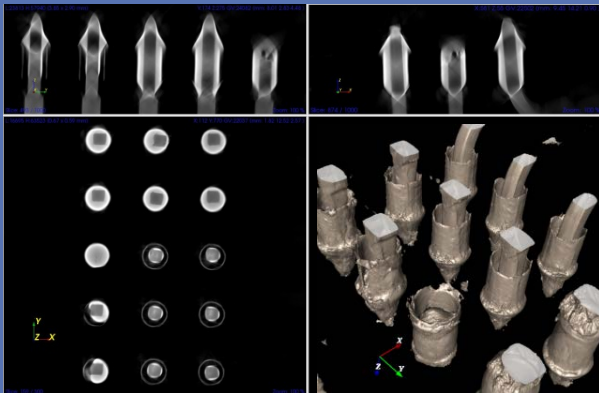
Software



## x|act 9.0

### 2D X-ray inspection software

- Combining ease of use with excellence in intuitive X-ray inspection
- Advanced defect coverage
- Live CAD overlay with PAD-ID and inspection results – at any time and at any viewing angle

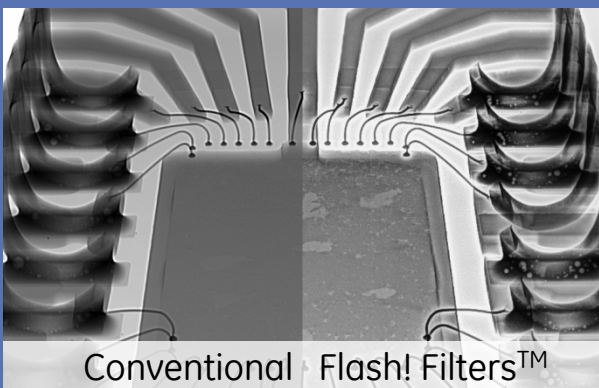


## planarCT

### Non destructive board inspection with CT

NEW

- Easy 2D plane and 3D volume inspection of complex printed circuit boards
- Excellent image quality and high magnification for wide defect coverage
- Slice and ROI CT volume evaluation in any direction with GE's 3D|viewer



Conventional Flash! Filters™

## Flash! Filters™ - image optimization

- Enables faster, more reliable failure detection
- Automates the filtering process of all grey scales present in each X-ray image
- Leads to significant time savings and defect coverage improvements



# X-ray System Upgrades

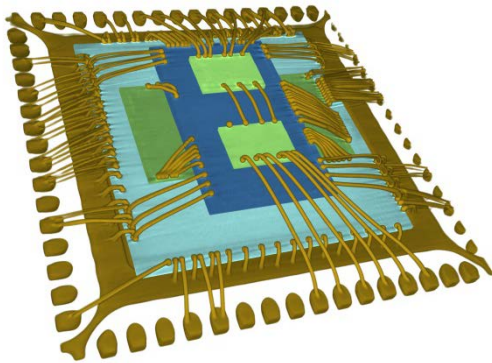
For phoenix microme|x and phoenix nanome|x inspection systems

Hardware



## High dynamic digital detectors

- High dynamic live imaging at full-resolution and corrections applied
- Endurance™ scintillator technology for best image quality due to minimized ghost image defect (lag)
- Temperature controlled for stable offsets over longer periods, enabling more consistent imaging and fewer calibrations



## Computed Tomography (CT)

- High contrast flat panel CT
- Offers three-dimensional images of the interior, even of hidden parts, of a sample for detailed failure analysis
- High quality CT results available within a few minutes



## Contact details:

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GE imagination at work